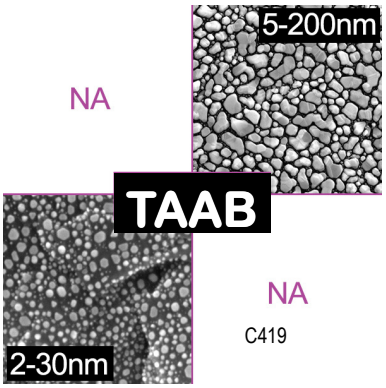
EM Calibration Standards

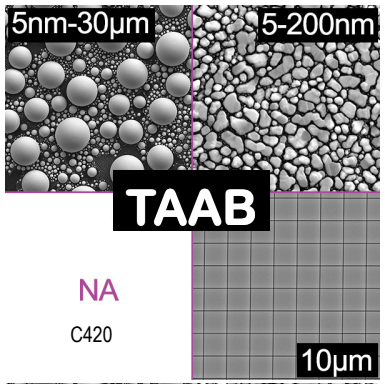
SEM Multi & Combination Test Standards



Gold on Carbon resolution standards with their varying sized gaps between gold crystals on a carbon substrate allow tests for resolution. as well as checking the quality of grey-level reproduction at high resolution. **Tin on Carbon** resolution standard is good for astigmatism and image shift measurements for SEMs. The **Ruled Silicon Grid** is excellent for comparing magnification and assessing distortion in the image field.

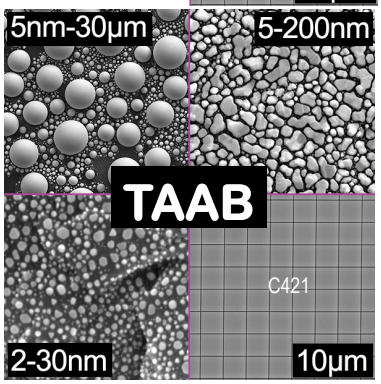
Gold and Hi Res Gold on Carbon

C419/P	Dual standard gold & Hi Res gold on carbon	12.5mm Ø pin stub
C419/H	Dual standard gold & Hi Res gold on carbon	15mm Ø Hiitachi Stub
C419/J	Dual standard gold & Hi Res gold on carbon	10mm Ø JEOL Stub



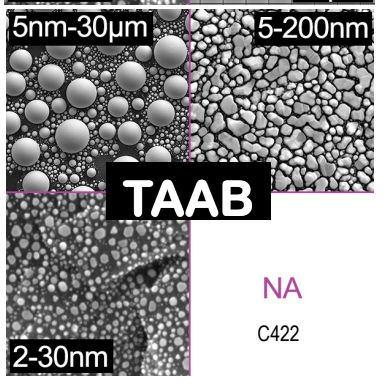
Tin and Gold on Carbon with Ruled Silicon

C420/P	Triple standard Tin & gold on carbon & ruled silicon	12.5mm Ø pin stub
C420/H	Triple standard Tin & gold on carbon & ruled silicon	15mm Ø Hitachi stub
C420/J	Triple standard Tin & gold on carbon & ruled silicon	10mm Ø JEOL stub



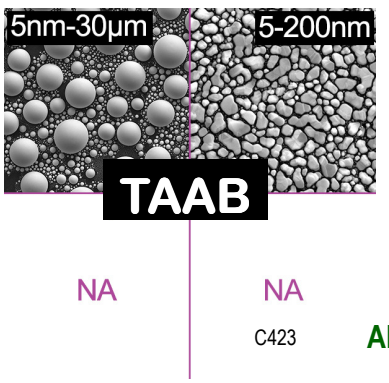
Tin, Gold and Hi Res Gold on Carbon with Ruled Silicon

C421P	Multi standard Tin, Gold, & Hi Res Gold on carbon and ruled Silicon	12.5mm Ø pin stub on
C421/H	Multi standard Tin, Gold & Hi Res Gold on carbon and ruled Silicon	15mm Ø Hitachi stub
C421/J	Multi standard Tin, Gold & Hi Res Gold on carbon and ruled Silicon	10mm Ø JEOL stub



Tin, Gold and Hi Res Gold on Carbon

C422//P	Triple standard Tin, Gold & Hi Res Gold on carbon	12.5mm Ø pin stub
C422//H	Triple standard Tin, Gold & Hi Res Gold on carbon	15mm Ø Hitachi stub
C422//J	Triple standard Tin, Gold & Hi Res Gold on carbon	10mm Ø JEOL stub



Tin and Gold on Carbon

C423/P	Dual standard Tin & Gold on carbon	12.5mm Ø pin stub
C423/H	Dual standard Tin & Gold on carbon	15mm Ø Hitachi stub
C423/J	Dual standard Tin & Gold on carbon	10mm Ø JEOL stub

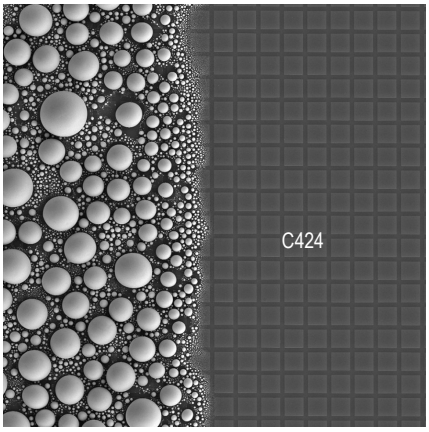
All combination standards can be mounted on a stub of your choice to special order

Phone: +44 (0) 118 981 7775 Fax: +44 (0) 118 981 7881 E-mail: sales@taab.co.uk

SEM Combination Test Standards cont

Tin on Ruled Silicon **Magnification and Resolution Standard**

C424/P	Dual standard Tin on Silicon resolution	12.5mm pin stub
C424/H	Dual standard Tin on Silicon resolution	15mm Hitachi stub
C424/J	Dual standard Tin on Silicon resolution	10mm JEOL stub
C424	Dual standard Tin on Silicon resolution	unmounted



Save time effort and money by using our SEM Multiple Combination Standards where you can move immediately from one standard to the next. Ideal for Benchtop SEMs.

SEM Magnification Calibration Standards

The **MCS series** calibration standards can be used with standard and table top SEMs. FESEM, FIB, Auger, SIMS and incident light microscope systems. They are an excellent replacement for the discontinued **SIRA** standard and can be used for **magnification** or **critical dimension** measurements. Two ranges are available with either **NIST traceability** or optionally **Individual Certification.**

MCS-1 for compact or table top SEMs with a scale from 2.5mm to 1µm covers **10x - 20,000x magnifications**.

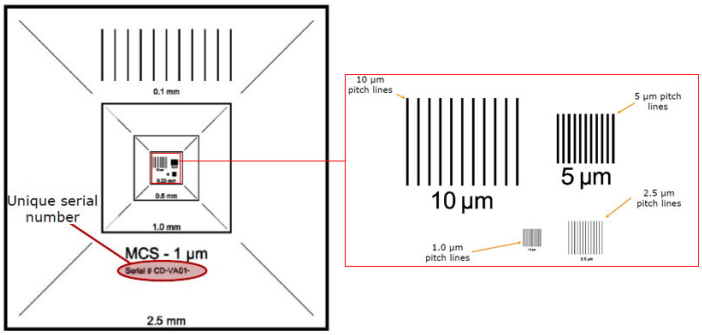
MCS-0.1 for larger SEM, FESEM and FIB systems with a scale from 2.5mm to 100nm covers **10x - 200,000x magnifications.**

Manufactured from fully conductive materials with all features on an ultra-flat plane, compatible with both SE and BSE imaging. Easily plasma cleaned.

Traceable uniformity 0.2% or better Certified uniformity 0.03% Supplied unmounted in Gel-Pak box

C425	MCS-1TR traceable calibration standard unmounted
C425/P	MCS-1TR on 12.7mm std pin stub
C425/Z	MCS-1TR on Zeiss 12.7mm pin stub
C425/J	MCS-1TR on JEOL 12.2mm stub
C425/H	MCS-1TR on Hitachi 15mm stub

C426	MCS-1CF NIST certified calibration std unmounted
C426/P	MCS-1CF NIST certified on 12.7mm std pin stub
C426/Z	MCS-1CF NIST certified on Zeiss 12.7mm pin stub
C426/J	MCS-1CF NIST certified on JEOL 12.2mm stub
C426/H	MCS-1CF NIST certified on Hitachi 15mm stub



C427	MCS-0.1TR traceable calibration standard unmounted
C427/P	MCS-0.1TR on 12.7mm standard pin stub
C427/Z	MCS-0.1TR on Zeiss 12.7mm pin stub
C427/J	MCS-0.1TR on JEOL 12.2mm stub
C427/H	MCS-0.1TR on Hitachi 15mm stub

C428	MCS-0.1CF NIST certified calibration std unmounted
C428/P	MCS-0.1CF NIST certified on 12.7mm std pin stub
C428/Z	MCS-0.1CF NIST certified on Zeiss 12.7mm pin stub
C428/J	MCS-0.1CF NIST certified on JEOL 12.2mm stub
C428/H	MCS-0.1CF NIST certified on Hitachi 15mm stub